

SEMI F47 Voltage Sag Immunity Test Report for Power Supply QS5.241



Other devices covered by this report:

QS5.241-ww Standard units

ww: blank Standard Units

C1 Version with conformal coated pc-boards

A1 Version with conformal coated pc-boards and ATEX/IECEx approval



SEMI F47 Test Report

Document Number QS5.241 Semi F47 Rev2 TR1

Approval Order Number LAB 20-803

Standards SEMI F47-0706 (July 2006)

SPECIFICATION FOR SEMICONDUCTOR PROCESSING EQUIPMENT - Voltage

Sag Immunity Compliance Tests

IEC 61000-4-11 2004 +A1:2017

Electromagnetic compatibility (EMC) - Part 4-11: Testing and measurement techniques - Voltage dips, short interruptions and voltage variations immunity tests for equipment with input current up to 16 A per phase

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Test Engineer Thomas Ramel

Test Date 18.06.2020 - 03.08.2020

Description of Test DeviceBuilt-in power supplies for DIN-Rail mounting

Devices under Evaluation QS5.241

Input: AC 100-240V, Output: DC 24-28V, 5A

S/N of Devices QS5.241: S/N: 20213585 A

Application Details Input voltage: 1-Phase AC 120V, 208V

Input frequency: 50 or 60Hz
Output load: 120W

Date: 03.08.2020 Document revision: 2 page 2/13



PASS/FAIL Criterions: In accordance with paragraph 7.8.2 a) of SEMI F47-0706

The output voltage is not allowed to deviated more than 5% of the initial

value

DC OK contact is not allowed to trigger during and after the test

Test Result:

PASS

The test device passed all essential SEMI F47-0706 tests according to the defined application details without any limitations and is qualified to bear the

following approval mark:

SEMI F47

Since DC power supplies, as covered in this test report, are only components of a semiconductor processing equipment, the tests of the SEMI F47 standard were conducted with selected rated characteristics of the DC power supply.

The system integrator of the final semiconductor processing equipment needs to judge if the results of this test report are compatible with the SEMI F47 requirements of his system or if test data under other operating conditions are additionally required.

The system integrator also needs to judge if the results of the inrush current peaks are compatible with the selected external fuses for input protection.

The system integrator also needs to be aware about aging effects. It is expected that the ride through time can be reduced by 15% at end of the specified lifetime expectancy.

A SEMI F47 certificate is not intended for this type of component, however the product fulfils the general requirements and can be marked with the following symbol.

Approved

Harald Etlinger Sr. Qualification Eng. PULS Vario GmbH, Vienna

Date of Approval

03.08.2020



Copy of marking plate:



List of Test Equipment

Туре	Model	Inventory number
Test generator	Kikusui PCR3000WE2	10381
el. Load	el. Load Chroma 63201	10046
Oscilloscope	LeCroy WS454	10130
Oscilloscope	LeCroy WS424	10127
Diffential Probe	Lecroy	10246
Current Probe	LeCroy CP30	10378

The test equipment complies with the requirements of IEC 61000-4-11.

The peak current capability of the test generator was evaluated according Annex A of IEC 61000-4-11 and is able to deliver minimum 32.7A.

Test Specification for SEMI F47 compliance

Voltage Sag Immunity according to the following table:

Sag depth#1	Duration	Duration at 50 Hz	Duration at 60 Hz
50%	200ms	10 cycles	12 cycles
70%	500ms	25 cycles	30 cycles
80%	1000ms	50 cycles	60 cycles

#1 Sag depth is expressed in percent of remaining nominal voltage. For example, during a 70% voltage sag on a 200 volt nominal system, the voltage is reduced during the sag to 140 volts and not 60 volts.



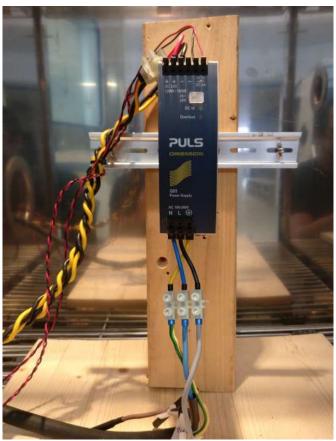
Test Setup

The unit under test in normal operating condition mounted in climate chamber.

The input is connected to an AC Source. The input voltage is measured with a 100:1 differential probe and the input current is measured with current probes. These probes are connected to oscilloscopes.

The output is connected to an active load. The output voltage is connected directly to the oscilloscope. "DC-OK" signal is also measured with an oscilloscope.

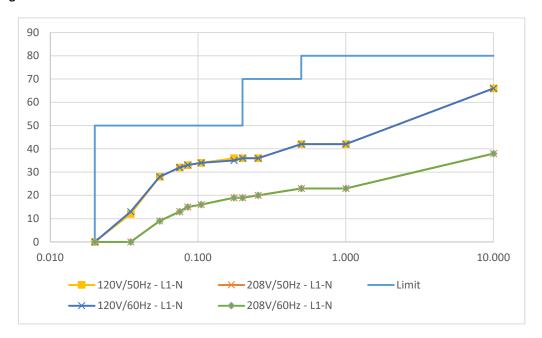
Input and output voltages are measured with oscilloscope #1 and input currents with oscilloscope #2.

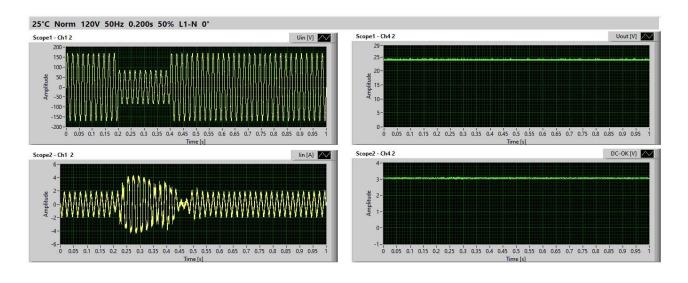


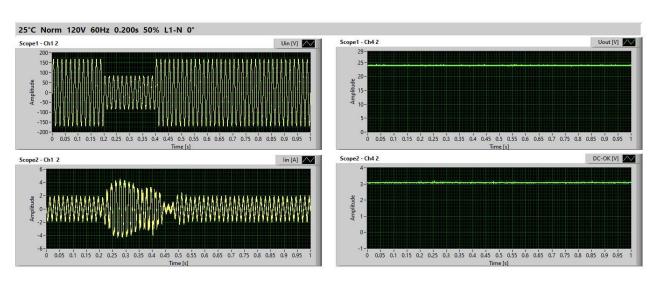




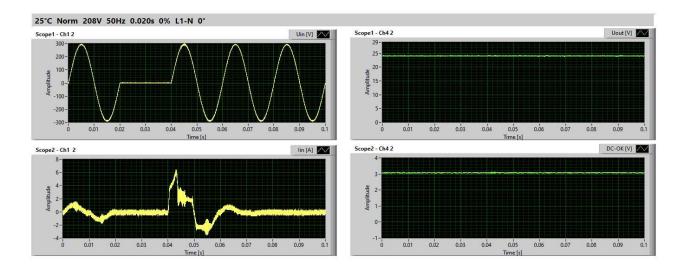
Voltage Sag Results

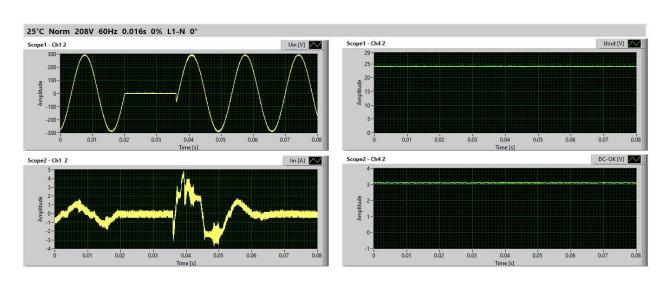














Conducted Tests at 120V 50Hz

Input Voltage 120Vac
Input Frequency 50Hz
Output Voltage 24V
Output Current 5A
Ambient Temperature 25°C

Sag duration [s]	Voltage remaining [%]	Pos. peak current [A]	Neg. peak current [A]
0.020	0	3.1	-3.4
0.200	50	4.4	-4.4
0.500	70	3	-3.1
1	80	2.5	-2.3
10	80	2.5	-2.7

Informational measurements

Sag duration [s]	Voltage remaining [%]	Sag duration [s]	Voltage remaining [%]
0.020	0	0.175	36
0.035	12	0.200	36
0.055	28	0.255	36
0.075	32	0.500	42
0.085	33	1	42
0.105	34	10	66

Conducted Tests at 120V 60Hz

Input Voltage 120Vac
Input Frequency 60Hz
Output Voltage 24V
Output Current 5A
Ambient Temperature 25°C

Sag duration [s]	Voltage remaining [%]	Pos. peak current [A]	Neg. peak current [A]
0.016	0	3.1	-3.3
0.200	50	4.5	-4.4
0.500	70	3.1	-3.3
1	80	2.5	-2.7
10	80	2.5	-2.7

Sag duration [s]	Voltage remaining [%]	Sag duration [s]	Voltage remaining [%]
0.016	0	0.175	35
0.035	13	0.200	36
0.055	28	0.255	36
0.075	32	0.500	42
0.085	33	1	42
0.105	34	10	66



Conducted Tests at 208V 50Hz

Input Voltage 208Vac
Input Frequency 50Hz
Output Voltage 24V
Output Current 5A
Ambient Temperature 25°C

Sag duration [s]	Voltage remaining [%]	Pos. peak current [A]	Neg. peak current [A]
0.020	0	6.4	-3.6
0.200	50	3.9	-3.3
0.500	70	4.1	-4.1
1	80	4.4	-4.2
10	80	3.9	-3.9

Informational measurements

Sag duration [s]	Voltage remaining [%]	Sag duration [s]	Voltage remaining [%]
0.020	0	0.175	19
0.035	0	0.200	19
0.055	9	0.255	20
0.075	13	0.500	23
0.085	15	1	23
0.105	16	10	38

Conducted Tests at 208V 60Hz

Input Voltage 208Vac
Input Frequency 60Hz
Output Voltage 24V
Output Current 5A
Ambient Temperature 25°C

Sag duration [s]	Voltage remaining [%]	Pos. peak current [A]	Neg. peak current [A]
0.016	0	4.8	-3.9
0.200	50	4.1	-2.3
0.500	70	4.1	-4.2
1	80	4.7	-3.4
10	80	3.9	-3.4

Sag duration [s]	Voltage remaining [%]	Sag duration [s]	Voltage remaining [%]
0.016	0	0.175	19
0.035	0	0.200	19
0.055	9	0.255	20
0.075	13	0.500	23
0.085	15	1	23
0.105	16	10	38



Inrush current measurements according 61000-4-11 at 208V 50Hz

Input Voltage 208Vac
Input Frequency 50Hz
Output Voltage 24V
Output Current 5A
Ambient Temperature 25°C

Peak input current measurements on unit under test:

First two measurements turn off input power for EUT for 5 minutes and then

Measure peak input current when AC turned on at 90°: 13.1A

Measure peak input current when AC turned on at 270°: 13.3A

Next two measurements turn on the input power for EUT for at least 1 minute then turn off input power for 5s and

on again.

Measure peak input current when AC turned on at 90°: 12.8A Measure peak input current when AC turned on at 270°: 13A

Inrush current measurements according 61000-4-11 at 208V 60Hz

Input Voltage 208Vac
Input Frequency 60Hz
Output Voltage 24V
Output Current 5A
Ambient Temperature 25°C

Peak input current measurements on unit under test:

First two measurements turn off input power for EUT for 5 minutes and then

Measure peak input current when AC turned on at 90°: 12.7A

Measure peak input current when AC turned on at 270°: 13A

on again.

Measure peak input current when AC turned on at 90°: 12.5A

Measure peak input current when AC turned on at 270°: 12.5A



Operating conditions and their influence in test results:

a) Ambient temperature:

Control measurements show that the ambient temperature has only a minor influence in the ride-through time test results.

Depending on the used topology to reduce the input inrush current, the ambient temperature can have a major influence in the arising peak current after the sag test. Therefore, tests were performed at ambient temperatures of 25°C and +60°C.

It is assumed that semiconductor processing equipment is never used at lower temperatures than +25°C. Although the power supply itself is specified down to -25°C, a test at such low temperatures is not performed.

b) Mains frequency 50Hz vs. 60Hz:

Control measurements show that 50Hz testing is more critical than 60Hz testing. Therefore, unless otherwise noted, all tests were performed with a mains frequency of 50Hz.

c) Output voltage 24V vs. 28V:

The ride-through time depend on the stored energy in the input capacitors and the amount of output power. The output voltage is not essential as long as the output power is constant.

The adjusted output voltage has no influence in input currents peaks after input voltage sags.

Therefore, unless otherwise noted, all tests were performed with an output voltage of 24Vdc.

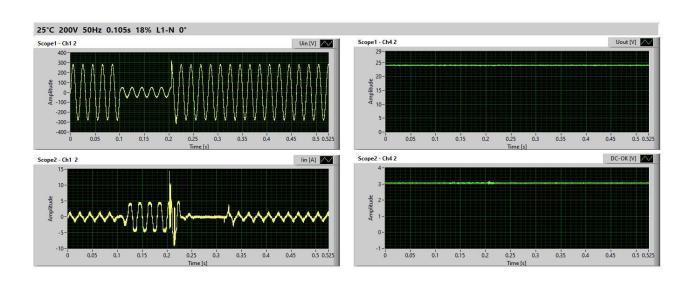


APPENDIX

Informational measurements at 200V

Input Voltage 200Vac
Input Frequency 50Hz
Output Voltage 24V
Output Current 5A
Ambient Temperature 25°C

Sag duration	Voltage remaining	Positive peak current	Negative peak current
[s]	[%]	[A]	[A]
0.020	0	7	-3.8
0.035	0	9.4	-14.1
0.055	12	9.7	-13.8
0.075	15	10.2	-13.6
0.085	17	13.3	-9.2
0.105	18	14.4	-9.2
0.175	20	9.1	-12.3
0.200	20	9.8	-7.3
0.255	21	8.9	-12
0.500	24	6.6	-4.7
1	24	6.1	-4.7
10	40	4.4	-3.6





Informational measurements at 230V

Input Voltage 230Vac
Input Frequency 50Hz
Output Voltage 24V
Output Current 5A
Ambient Temperature 25°C

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Sag duration	Voltage remaining	Positive peak current	Negative peak current
[s]	[%]	[A]	[A]
0.020	0	4.4	-3.8
0.035	0	6.6	-13.6
0.055	0	11.6	-13.3
0.075	8	11.3	-14.4
0.085	10	14.4	-11.4
0.105	12	14.5	-11.7
0.175	16	11.3	-13.8
0.200	17	11.4	-8.9
0.255	17	10.5	-13.3
0.500	21	8.3	-4.7
1	21	7.2	-4.5
10	34	5.3	-4.1

